## Issue Classification

App	lication	/Control	ΙN	l
-----	----------	----------	----	---

10757650

Examiner

Flores, Leon

## Applicant(s)/Patent Under Reexamination

MAUPIN, PATRICK EVAN

Art Unit

2611

ORIGINAL						INTERNATIONAL CLASSIFICATION										
CLASS SUBCLA				SUBCLASS		CLAIMED					NON-CL/					AIMED
375 295				Η	0	4	L	27 / 04 (2006.0	1.01)	•						
	CR	OSS REF	ERENCE(	Ś)						•						
CLASS SUBCLASS (ONE SUBCLASS PE			S PER BLO	CK)	_										<del></del>	
341	51															
	ļ ·															
						_										•
		<u>.</u>								II.	∤			<u> </u>		
					!	ļ										
						ļ	!									
	ļ	•	-			ļ								-		
	·													_		
															<del>   </del>	
	<u> </u>						-;-								$\vdash$	
	1			,		-										
						<del>                                     </del>							<del>                                     </del>		<del>   </del>	
			<del> </del>													
<u>.                                    </u>	1						-				$\dashv$					
			· · · · · ·			<u> </u>					•					
											<u> </u>					
· · · · · · · · · · · · · · · · · · ·												-				
			·							, , , , , , , , , , , , , , , , , , , ,			<u> </u>	<u> </u>		
	ļ															
						<u> </u>								<u> </u>		
	<u> </u>					<u> </u>		<u> </u>	<u></u>				<u> </u>			
Flores, Leon 7/18/2007 (Assistant Examiner) (Date)		0110	Dand Parpe DAVID C. PAYNE SUPERVISORY PATENT EXAMINER				(AMINER	Total Claims Allowed:								
											_					
• .		David C. Payne · 7/18/2007					/18/2007	O.G. Print Claim(s)				O.G. Print Figure				
(Legal Instruments (Date) Examiner)		(Primary Examiner) (Date)					Date)	1 1								